

測試報告

Test Report

號碼(No.): ETR23405074

日期(Date): 02-May-2023

頁數(Page): 1 of 5

穩懋半導體股份有限公司 (WIN SEMICONDUCTORS CORP.)

桃園市龜山區華亞科技園區科技七路35號 (NO.35, KEJI 7TH RD., HWAYA TECHNOLOGY PARK, GUISHAN DISTRICT, TAOYUAN CITY 33383, TAIWAN)

以下測試樣品係由申請廠商所提供及確認 (The following sample(s) was/were submitted and identified by the applicant as) :

送樣廠商(Sample Submitted By) : 穩懋半導體股份有限公司 (WIN SEMICONDUCTORS CORP.)

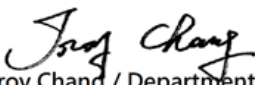
樣品名稱(Sample Name) : GaN WAFER

收件日(Sample Receiving Date) : 21-Apr-2023

測試期間(Testing Period) : 21-Apr-2023 to 28-Apr-2023

測試需求(Test Requested) : 依據客戶要求進行測試，測試項目請參閱測試結果表格。(Testing item(s) is/are specified by client. Please refer to result table for testing item(s).)

測試結果(Test Results) : 請參閱下一頁 (Please refer to following pages.)


Troy Chang / Department Manager
Signed for and on behalf of
SGS TAIWAN LTD.
Chemical Laboratory - Taipei



PIN CODE: 27512FB8

This document is issued by the Company subject to its General Conditions of Service printed overleaf, available on request or accessible at <https://www.sgs.com.tw/terms-of-service> and, for electronic format documents, subject to Terms and Conditions for Electronic Documents at <https://www.sgs.com.tw/terms-of-service>. Attention is drawn to the limitation of liability, indemnification and jurisdiction issues defined therein. Any holder of this document is advised that information contained hereon reflects the Company's findings at the time of its intervention only and within the limits of client's instruction, if any. The Company's sole responsibility is to its Client and this document does not exonerate parties to a transaction from exercising all their rights and obligations under the transaction documents. This document cannot be reproduced, except in full, without prior written approval of the Company. Any unauthorized alteration, forgery or falsification of the content or appearance of this document is unlawful and offenders may be prosecuted to the fullest extent of the law. Unless otherwise stated the results shown in this test report refer only to the sample(s) tested.

測試報告

Test Report

號碼(No.): ETR23405074

日期(Date): 02-May-2023

頁數(Page): 2 of 5

穩懋半導體股份有限公司 (WIN SEMICONDUCTORS CORP.)

桃園市龜山區華亞科技園區科技七路35號 (NO.35, KEJI 7TH RD., HWAYA TECHNOLOGY PARK, GUIZHAN DISTRICT, TAOYUAN CITY 33383, TAIWAN)

測試部位敘述 (Test Part Description)

No.1 : 晶圓 (WAFER)

測試結果 (Test Results)

測試項目 (Test Items)	測試方法 (Method)	單位 (Unit)	MDL	結果 (Result)
				No.1
全氟辛烷磺酸及其鹽類 (PFOS and its salts) (CAS No.: 1763-23-1 and its salts)	參考CEN/TS 15968: 2010 · 以液相層析串聯質譜儀分析。(With reference to CEN/TS 15968: 2010, analysis was performed by LC/MS/MS.)	mg/kg	0.01	n.d.
全氟辛酸及其鹽類 (PFOA and its salts) (CAS No.: 335-67-1 and its salts)	參考CEN/TS 15968: 2010 · 以液相層析串聯質譜儀分析。(With reference to CEN/TS 15968: 2010, analysis was performed by LC/MS/MS.)	mg/kg	0.01	n.d.
鈹 (Be) (Beryllium (Be)) (CAS No.: 7440-41-7)	參考US EPA 3050B: 1996 · 以感應耦合電漿發射光譜儀分析。(With reference to US EPA 3050B: 1996, analysis was performed by ICP-OES.)	mg/kg	2	n.d.
銻 (Sb) (Antimony (Sb)) (CAS No.: 7440-36-0)	參考US EPA 3050B: 1996 · 以感應耦合電漿發射光譜儀分析。(With reference to US EPA 3050B: 1996, analysis was performed by ICP-OES.)	mg/kg	2	n.d.

備註(Note) :

1. mg/kg = ppm ; 0.1wt% = 0.1% = 1000ppm
2. MDL = Method Detection Limit (方法偵測極限值)
3. n.d. = Not Detected (未檢出); 小於MDL / Less than MDL
4. 全氟辛烷磺酸及其鹽類包含等物質 (PFOS and its salts including) :
CAS No.: 1763-23-1, 2795-39-3, 29457-72-5, 29081-56-9, 70225-14-8, 56773-42-3, 251099-16-8, 307-35-7, 91036-71-4, 4021-47-0 and others.
5. 全氟辛酸及其鹽類包含等物質 (PFOA and its salts including) :
CAS No.: 335-67-1, 335-95-5, 2395-00-8, 335-93-3, 335-66-0, 3825-26-1 and others.

This document is issued by the Company subject to its General Conditions of Service printed overleaf, available on request or accessible at <https://www.sgs.com.tw/terms-of-service> and, for electronic format documents, subject to Terms and Conditions for Electronic Documents at <https://www.sgs.com.tw/terms-of-service>. Attention is drawn to the limitation of liability, indemnification and jurisdiction issues defined therein. Any holder of this document is advised that information contained hereon reflects the Company's findings at the time of its intervention only and within the limits of client's instruction, if any. The Company's sole responsibility is to its Client and this document does not exonerate parties to a transaction from exercising all their rights and obligations under the transaction documents. This document cannot be reproduced, except in full, without prior written approval of the Company. Any unauthorized alteration, forgery or falsification of the content or appearance of this document is unlawful and offenders may be prosecuted to the fullest extent of the law. Unless otherwise stated the results shown in this test report refer only to the sample(s) tested.

測試報告

Test Report

號碼(No.): ETR23405074

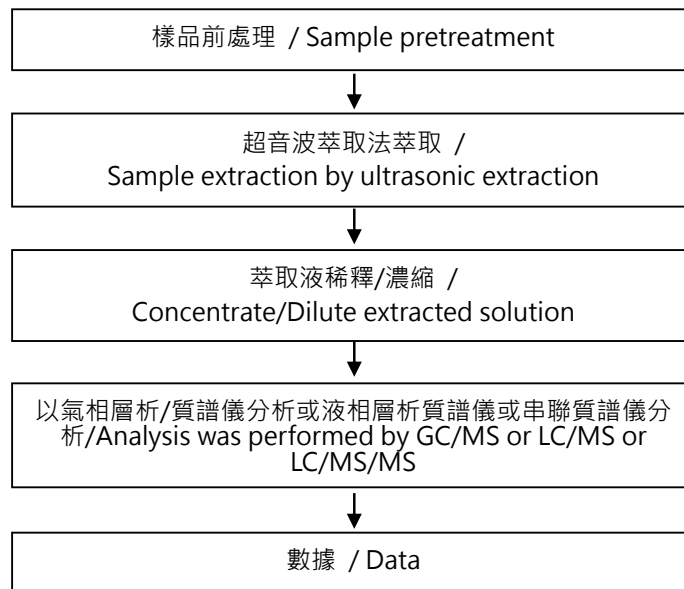
日期(Date): 02-May-2023

頁數(Page): 3 of 5

穩懋半導體股份有限公司 (WIN SEMICONDUCTORS CORP.)

桃園市龜山區華亞科技園區科技七路35號 (NO.35, KEJI 7TH RD., HWAYA TECHNOLOGY PARK, GUIZHAN DISTRICT, TAOYUAN CITY 33383, TAIWAN)

全氟化合物(包含全氟辛酸/全氟辛烷磺酸/其相關化合物等等)分析流程圖 / Analytical flow chart – PFAS (including PFOA/PFOS/its related compound, etc.)



This document is issued by the Company subject to its General Conditions of Service printed overleaf, available on request or accessible at <https://www.sgs.com.tw/terms-of-service> and, for electronic format documents, subject to Terms and Conditions for Electronic Documents at <https://www.sgs.com.tw/terms-of-service>. Attention is drawn to the limitation of liability, indemnification and jurisdiction issues defined therein. Any holder of this document is advised that information contained hereon reflects the Company's findings at the time of its intervention only and within the limits of client's instruction, if any. The Company's sole responsibility is to its Client and this document does not exonerate parties to a transaction from exercising all their rights and obligations under the transaction documents. This document cannot be reproduced, except in full, without prior written approval of the Company. Any unauthorized alteration, forgery or falsification of the content or appearance of this document is unlawful and offenders may be prosecuted to the fullest extent of the law. Unless otherwise stated the results shown in this test report refer only to the sample(s) tested.

測試報告

Test Report

號碼(No.): ETR23405074

日期(Date): 02-May-2023

頁數(Page): 4 of 5

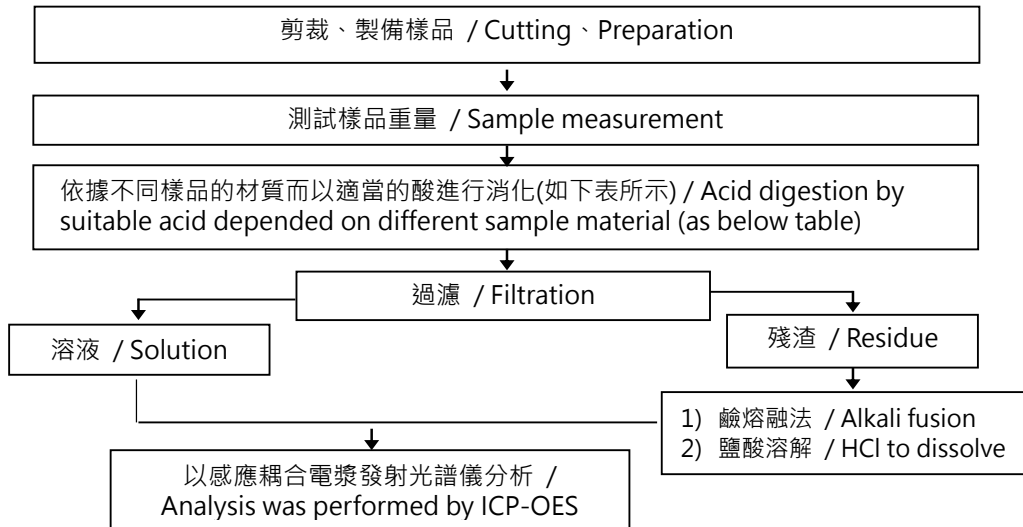
穩懋半導體股份有限公司 (WIN SEMICONDUCTORS CORP.)

桃園市龜山區華亞科技園區科技七路35號 (NO.35, KEJI 7TH RD., HWAYA TECHNOLOGY PARK, GUIZHAN DISTRICT, TAOYUAN CITY 33383, TAIWAN)

元素以 ICP-OES 分析的消化流程圖

(Flow chart of digestion for the elements analysis performed by ICP-OES)

根據以下的流程圖之條件，樣品已完全溶解。 / These samples were dissolved totally by pre-conditioning method according to below flow chart.



鋼,銅,鋁,焊錫 / Steel, copper, aluminum, solder	王水,硝酸,鹽酸,氫氟酸,雙氧水 / Aqua regia, HNO ₃ , HCl, HF, H ₂ O ₂
玻璃 / Glass	硝酸,氫氟酸 / HNO ₃ , HF
金,鉑,鈀,陶瓷 / Gold, platinum, palladium, ceramic	王水 / Aqua regia
銀 / Silver	硝酸 / HNO ₃
塑膠 / Plastic	硫酸,雙氧水,硝酸,鹽酸 / H ₂ SO ₄ , H ₂ O ₂ , HNO ₃ , HCl
其他 / Others	加入適當的試劑至完全溶解 / Added appropriate reagent to total digestion

This document is issued by the Company subject to its General Conditions of Service printed overleaf, available on request or accessible at <https://www.sgs.com.tw/terms-of-service> and, for electronic format documents, subject to Terms and Conditions for Electronic Documents at <https://www.sgs.com.tw/terms-of-service>. Attention is drawn to the limitation of liability, indemnification and jurisdiction issues defined therein. Any holder of this document is advised that information contained hereon reflects the Company's findings at the time of its intervention only and within the limits of client's instruction, if any. The Company's sole responsibility is to its Client and this document does not exonerate parties to a transaction from exercising all their rights and obligations under the transaction documents. This document cannot be reproduced, except in full, without prior written approval of the Company. Any unauthorized alteration, forgery or falsification of the content or appearance of this document is unlawful and offenders may be prosecuted to the fullest extent of the law. Unless otherwise stated the results shown in this test report refer only to the sample(s) tested.

測試報告

Test Report

號碼(No.): ETR23405074

日期(Date): 02-May-2023

頁數(Page): 5 of 5

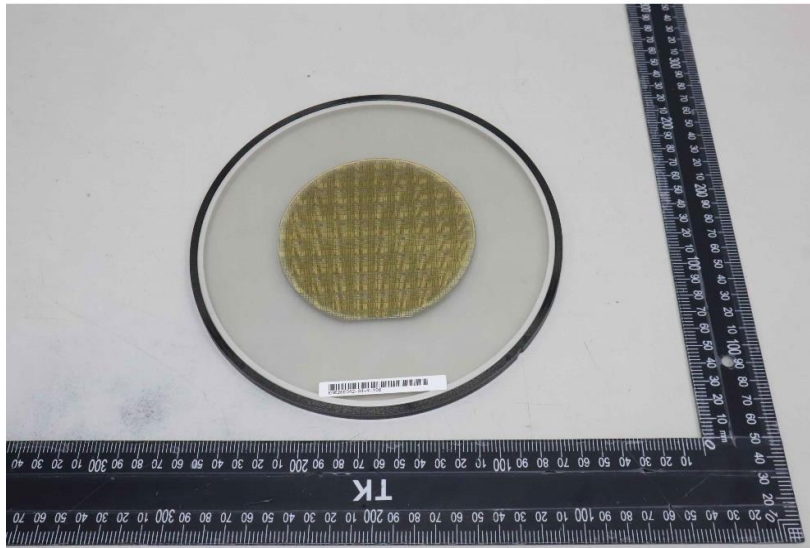
穩懋半導體股份有限公司 (WIN SEMICONDUCTORS CORP.)

桃園市龜山區華亞科技園區科技七路35號 (NO.35, KEJI 7TH RD., HWAYA TECHNOLOGY PARK, GUISHAN DISTRICT, TAOYUAN CITY 33383, TAIWAN)

* 照片中如有箭頭標示，則表示為實際檢測之樣品/部位。*

(The tested sample / part is marked by an arrow if it's shown on the photo.)

ETR23405074



** 報告結尾 (End of Report) **

This document is issued by the Company subject to its General Conditions of Service printed overleaf, available on request or accessible at <https://www.sgs.com.tw/terms-of-service> and, for electronic format documents, subject to Terms and Conditions for Electronic Documents at <https://www.sgs.com.tw/terms-of-service>. Attention is drawn to the limitation of liability, indemnification and jurisdiction issues defined therein. Any holder of this document is advised that information contained hereon reflects the Company's findings at the time of its intervention only and within the limits of client's instruction, if any. The Company's sole responsibility is to its Client and this document does not exonerate parties to a transaction from exercising all their rights and obligations under the transaction documents. This document cannot be reproduced, except in full, without prior written approval of the Company. Any unauthorized alteration, forgery or falsification of the content or appearance of this document is unlawful and offenders may be prosecuted to the fullest extent of the law. Unless otherwise stated the results shown in this test report refer only to the sample(s) tested.